Accepted Manuscript

Topic-based Software Defect Explanation

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PII: S0164-1212(16)30052-8
DOI: 10.1016/j.jss.2016.05.015
Reference: JSS 9752

To appear in: *The Journal of Systems & Software*

Received date: 31 January 2015
Revised date: 29 April 2016
Accepted date: 3 May 2016

Please cite this article as: Tse-Hsun Chen, Weiyi Shang, Meiyappan Nagappan, Ahmed E. Hassan, Stephen W. Thomas, Topic-based Software Defect Explanation, *The Journal of Systems & Software* (2016), doi: 10.1016/j.jss.2016.05.015

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Highlights

- Some topics are more defect-prone than others.
- Defect-prone topics are likely to remain so over time.
- Our topic-based metrics provide additional defect explanatory to baseline metrics.
- Our metrics outperform state-of-the-art topic-based cohesion and coupling metrics.

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